

#JH
6/100
pms

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Moshe Finarov; Eran Dvir; Eli Haimovich; Benjamin Shulman
Assignee: Nova Measuring Instruments, Ltd.
Title: APPARATUS FOR OPTICAL INSPECTION OF WAFERS DURING POLISHING
Serial No.: Unknown Filed: Herewith
Examiner: Unknown Group Art Unit: Unknown
Docket No.: M-3417-2C US

San Jose, California
February 4, 2000

BOX PATENT APPLICATION
ASSISTANT COMMISSIONER FOR PATENTS
WASHINGTON, D. C. 20231

Dear Sir:

PRELIMINARY AMENDMENT

This Paper is submitted prior to examination of the above-listed patent application, a Continuation of U.S. Patent Application Serial No. 08/497,382, filed on June 29, 1995, (hereinafter "the Parent Application"), which has been allowed.

Please amend the Patent Application as follows.

IN THE DRAWINGS

Please amend FIGS. 6, 7, 8 and 9 as indicated in red ink on the enclosed copies of those figures as filed in Parent Application.

IN THE SPECIFICATION

On page 1, immediately above FIELD OF THE INVENTION, insert the following section.